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- D-Type Flip-Flops in a Single Package With 3-State Bus Driving True Outputs
- Full Parallel Access for Loading
- Buffered Control Inputs
- Package Options Include Plastic Small-Outline (DW), Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

description

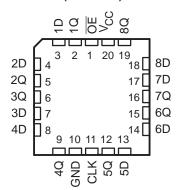
These octal D-type edge-triggered flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively lowimpedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

On the positive transition of the clock (CLK) input, the Q outputs are set to the logic levels set up at the data (D) inputs.

A buffered output-enable (\overline{OE}) input places the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without interface or pullup components.

SN54ALS374A, SN54AS374 J PACKAGE
SN74ALS374A, SN74AS374 DW OR N PACKAGE
(TOP VIEW)

SN54ALS374A, SN54AS374...FK PACKAGE (TOP VIEW)



OE does not affect internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ALS374A and SN54AS374 are characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS374A and SN74AS374 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each flip-flop)								
	INPUTS		OUTPUT					
OE	CLK	D	Q					
L	\uparrow	Н	Н					
L	\uparrow	L	L					
L	H or L	Х	Q ₀					
н	Х	Х	Z					



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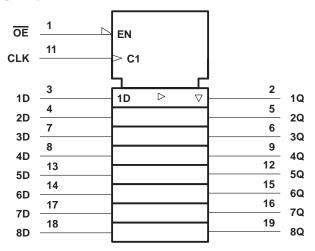
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



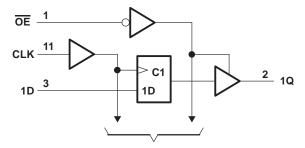
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logic symbol[†]



logic diagram (positive logic)



To Seven Other Channels

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage, V _{CC}	
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	
Operating free-air temperature range, T _A : SN54ALS374A	-55°C to 125°C
SN74ALS374A	0°C to 70°C
Storage temperature range, T _{stg}	-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS374A SN74ALS374A MIN NOM MAX MIN NOM MAX		'4A	SN74ALS374A			UNIT
				MAX				
V _{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-1			-2.6	mA
IOL	Low-level output current			12			24	mA
fclock	Clock frequency	0		30	0		35	MHz
t _w	Pulse duration, CLK high or low	16.5			14			ns
t _{su}	Setup time, data before CLK^\uparrow	10			10			ns
t _h	Hold time, data after CLK↑	4			0			ns
TA	Operating free-air temperature	-55		125	0		70	°C



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PARAMETER	TEST CONDITIONS		SN5	4ALS37	'4A	SN74ALS374A			LINUT
PARAMETER	TEST C	UNDITIONS	MIN	TYP [†]	MAX	MIN	TYP [†]	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lı = – 18 mA			-1.5			-1.5	V
	$V_{CC} = 4.5 V \text{ to } 5.5 V,$	I _{OH} = -0.4 mA	V _{CC} -2			V _{CC} -2			
VOH	V _{CC} = 4.5 V	I _{OH} = -1 mA	2.4	3.3					V
	$v_{\rm CC} = 4.5 v$	I _{OH} = -2.6 mA				2.4	3.2		
Max	V _{CC} = 4.5 V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL		I _{OL} = 24 mA					0.35	0.5	V
IOZH	V _{CC} = 5.5 V,	V _O = 2.7 V			20			20	μΑ
IOZL	V _{CC} = 5.5 V,	V _O = 0.4 V			-20			-20	μA
lj	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
Чн	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μA
١ _{IL}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.2			-0.2	mA
IO‡	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
		Outputs high		11	20		11	19	
ICC	$V_{CC} = 5.5 V$	Outputs low		19	28		19	28	mA
		Outputs disabled		20	31		20	31	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

switching characteristics (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C C _L R1 R2 T _A	UNIT			
			SN54AL	S374A	SN74AL		
			MIN	MAX	MIN	MAX	
fmax			30		35		MHz
tPLH	CLK	0	3	14	3	12	ns
^t PHL	OLK	Q	5	17	5	16	115
^t PZH	OE	0	5	18	3	17	ns
tPZL	UE	Q	6	21	5	18	115
^t PHZ	OE	Q	2	11	1	10	ns
^t PLZ		Q	3	19	2	18	115

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC}	
Voltage applied to a disabled 3-state output	
Operating free-air temperature range, T _A : SN54AS374	
SN74AS374	0°C to 70°C
Storage temperature range, T _{stg}	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SN	SN54AS374 SN74AS374			4	UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage		4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.7			0.8	V
IOH	High-level output current				-12			-15	mA
IOL	Low-level output current				32			48	mA
fclock*	Clock frequency		0		100	0		125	MHz
* *	Pulse duration	CLK high	5.5			4			
t _w *	Fuse duration	CLK low	3			3			ns
t _{su} *	Setup time, data before CLK↑		3			2			ns
t _h *	Hold time, data after CLK↑		3			2			ns
TA	Operating free-air temperature		-55		125	0		70	°C

* On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.



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PARAMETER		TEST CONDITIONS		SN	154AS37	'4	SN	174AS37	'4	LINUT
				MIN	TYP†	MAX	MIN	TYP†	MAX	UNIT
Vik		V _{CC} = 4.5 V,	lı = – 18 mA			-1.2			-1.2	V
		V_{CC} = 4.5 V to 5.5 V,	$I_{OH} = -2 \text{ mA}$	V _{CC} -2	2		V _{CC} -2	2		
∨он		V _{CC} = 4.5 V	I _{OH} = -12 mA	2.4	3.2					V
		$v_{\rm CC} = 4.5 v$	I _{OH} = -15 mA				2.4	3.3		
			I _{OL} = 32 mA		0.29	0.5				V
VOL		$V_{CC} = 4.5 V$	I _{OL} = 48 mA					0.34	0.5	v
IOZH		V _{CC} = 5.5 V,	V _O = 2.7 V			50			50	μΑ
IOZL		V _{CC} = 5.5 V,	V _O = 0.4 V			-50			-50	μΑ
lj –		V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
IIН		V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
	OE, CLK		N 0.4 M			-0.5			-0.5	A
۱IL	Data $V_{CC} = 5.5 V$,		$V_{I} = 0.4 V$		-3				-2	mA
10‡	-	V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA
			Outputs high		77	120		77	120	
ICC		V _{CC} = 5.5 V	Outputs low		84	128		84	128	mA
			Outputs disabled		84	128		84	128	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.

[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

switching characteristics (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L R1 R2	_ = 50 pF = 500 Ω 2 = 500 Ω	2,	3	UNIT
			SN54A	S374	SN74A	S374	
			MIN	MAX	MIN	MAX	
fmax*			100		125		MHz
tPLH	CLK	0	3	11	3	8	ns
t _{PHL}	OLK	Q	4	11.5	4	9	115
^t PZH	OE	0	2	7	2	6	ns
tPZL	UE	Q	3	11	3	10	115
^t PHZ	OE	Q	2	10	2	6	ns
tPLZ		Q	2	7	2	6	115

* On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested. § For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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APPLICATION INFORMATION

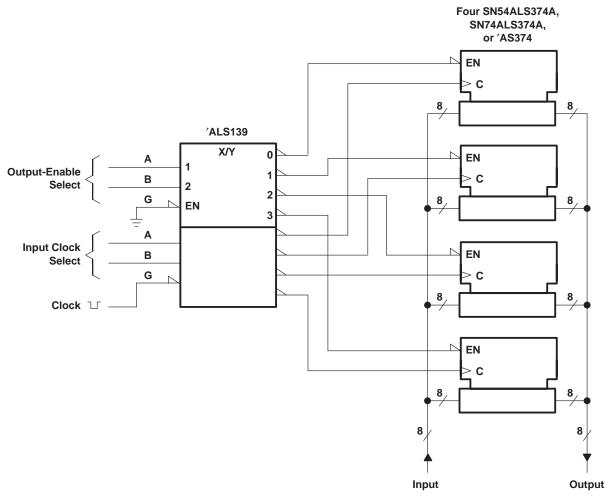
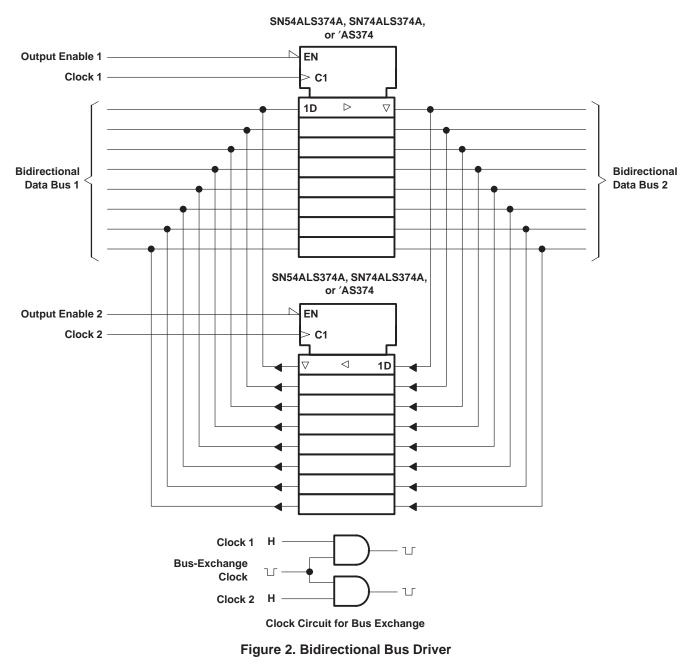


Figure 1. Expandable 4-Word by 8-Bit General File Register



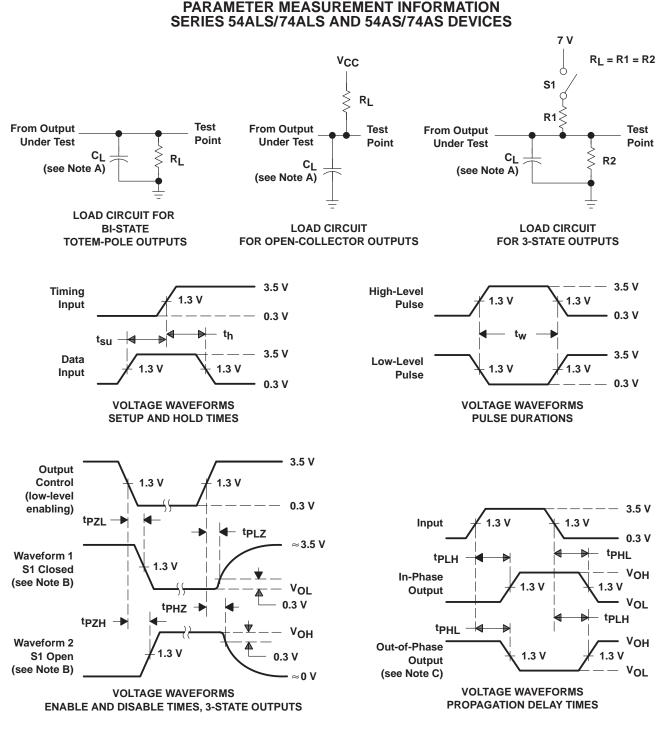
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APPLICATION INFORMATION





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NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, t_r = t_f = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 3. Load Circuits and Voltage Waveforms



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